



Electron Trigger Efficiency Determination from Data

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Introduction

- Trigger efficiency is an important systematic
- In order to reduce reliance on Monte Carlo (MC) it is important to have ways of **determining this from data.**
- For both **isolated** and **unisolated** triggers.
- Need to know what affects electron trigger efficiency.
- Important factors are, for example;
 - Fakes
 - Electron Kinematics; E_t , η , ϕ etc
 - Event topologies; Jet N, Jet Pt etc
- In this talk I will present a method for determining electron trigger efficiency from data that takes all of these into account.
- All results shown are for rel 13.0.X L1+L2+EF.

Definitions

- Trigger efficiency is calculated w.r.t 'good offline' reconstructed electrons;
 - Where a good offline reconstructed electron is defined as;
 - **SUSY CSC note electron definition**, (tighter than for typical trigger studies).
 - egamma electrons
 - IsEM medium
 - $P_t > 10$ GeV
 - $\text{Eta} < 2.5$
 - No crack (exclude $1.37 < |\text{eta}| < 1.52$)
 - Isolation; require $\text{etcone20} < 10$ GeV
 - Jet Veto in cone 0.4; electron is discarded if within a jet
- Efficiency (as a function of E_t) is defined as;

$$\text{Efficiency} = N1(E_t) / N2(E_t)$$

- Where;

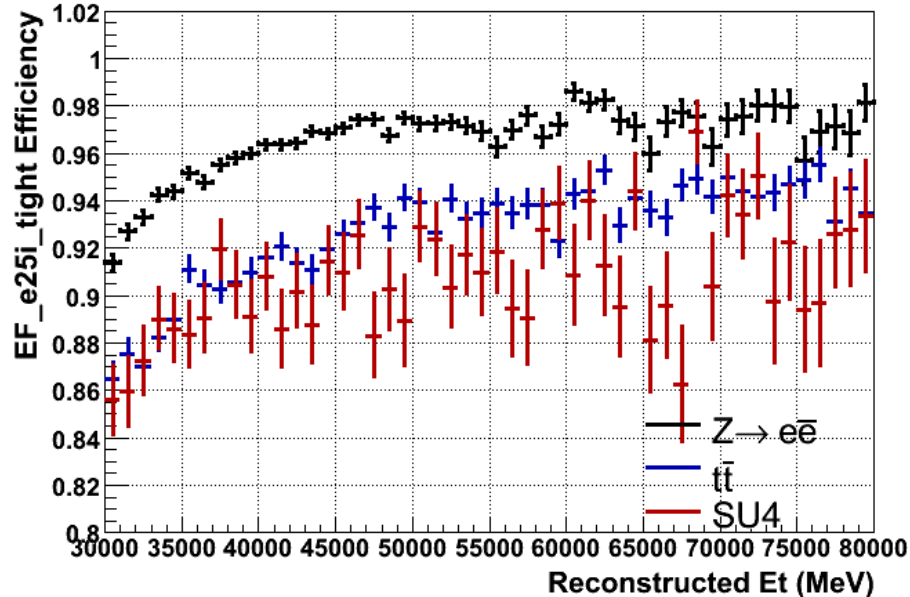
N1 = Good offline reconstructed electrons associated to objects passing trigger, (using Delta R matching).

N2 = Good offline reconstructed electrons.

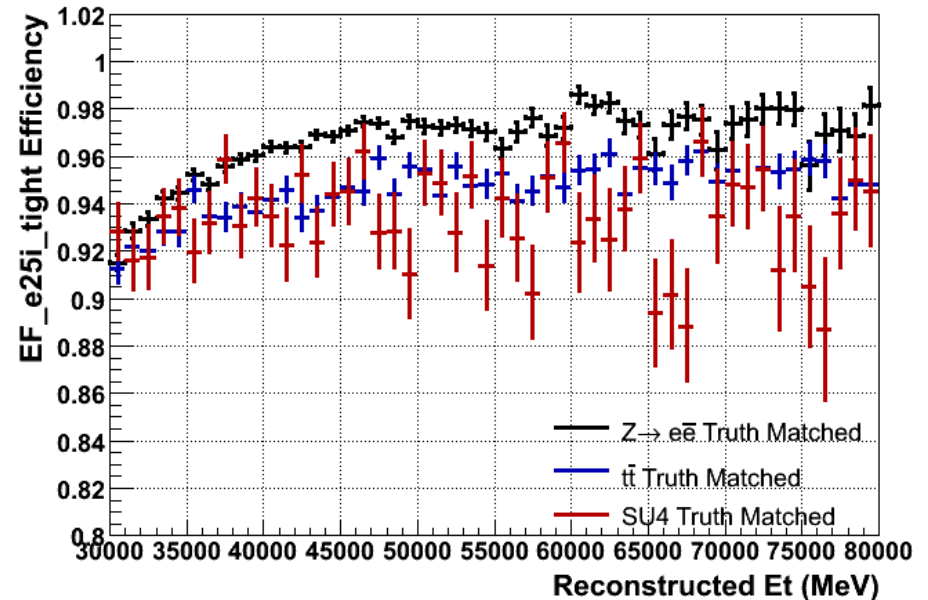
Truth Match definitions

- Use truth matched 'signal' electrons for now.

EF_e25i_tight



All reconstructed

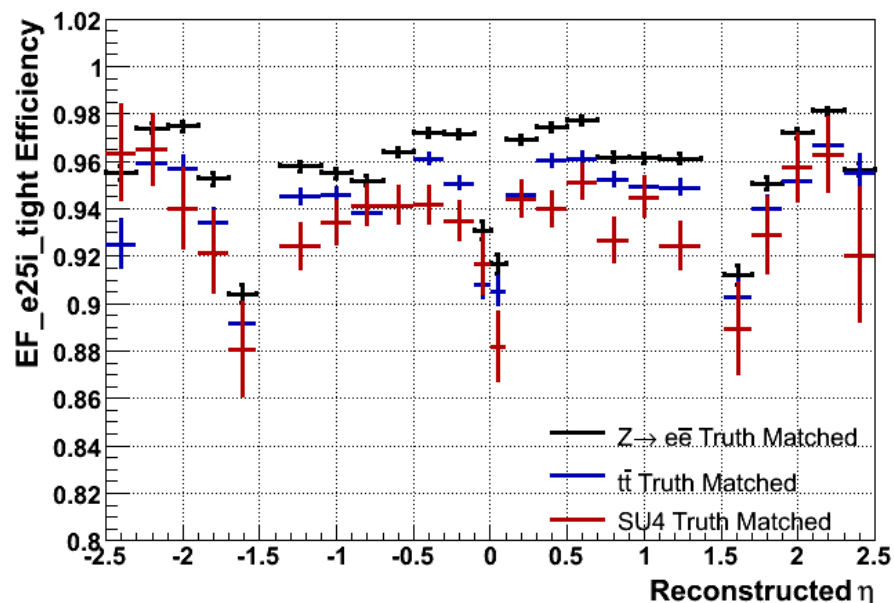
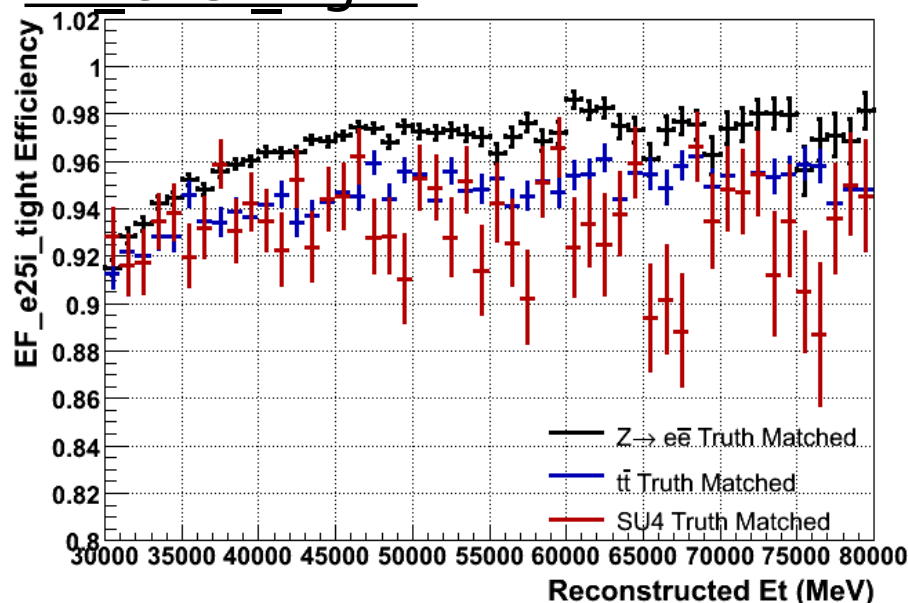


Reconstructed Matched to Truth

- Where 'signal' is defined as prompt electrons from **W**, Z or **SUSY** particle decays.

Monte Carlo Trigger Efficiencies

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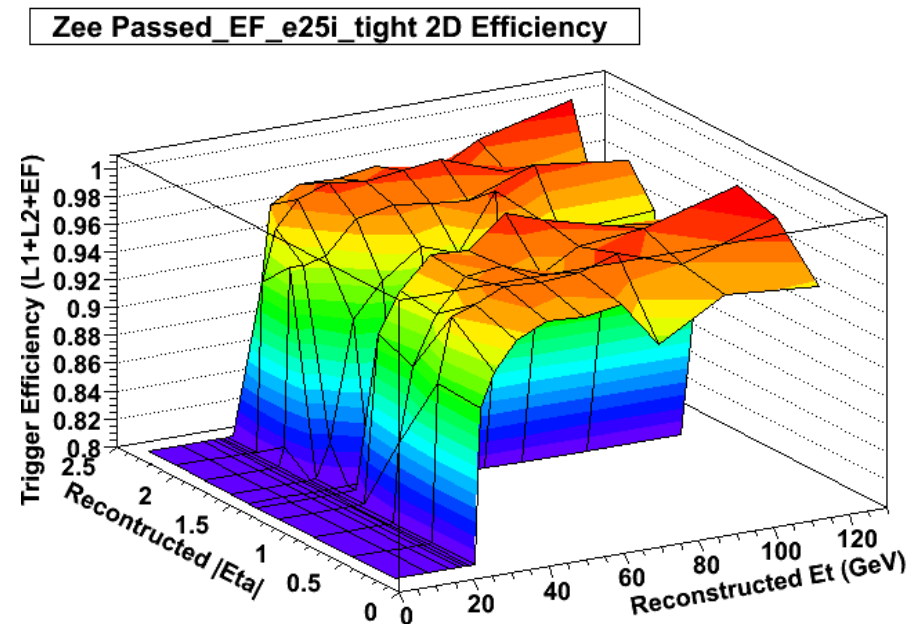


- We can see that for different samples Efficiency as a function of E_t or E_t integrated over all other variables varies.
- $Ttbar$ and $SU4$ samples show lower efficiency than $Z \rightarrow ee$.
- When studying trigger efficiencies we need to account for these differences.
- Do differences come from different electron kinematics or something else.

Data Driven Trigger efficiency measurement

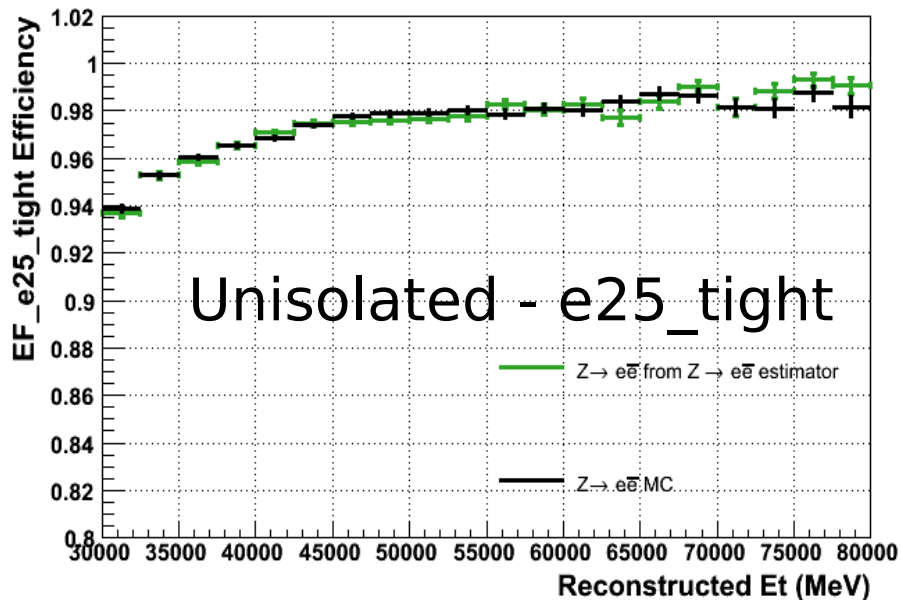
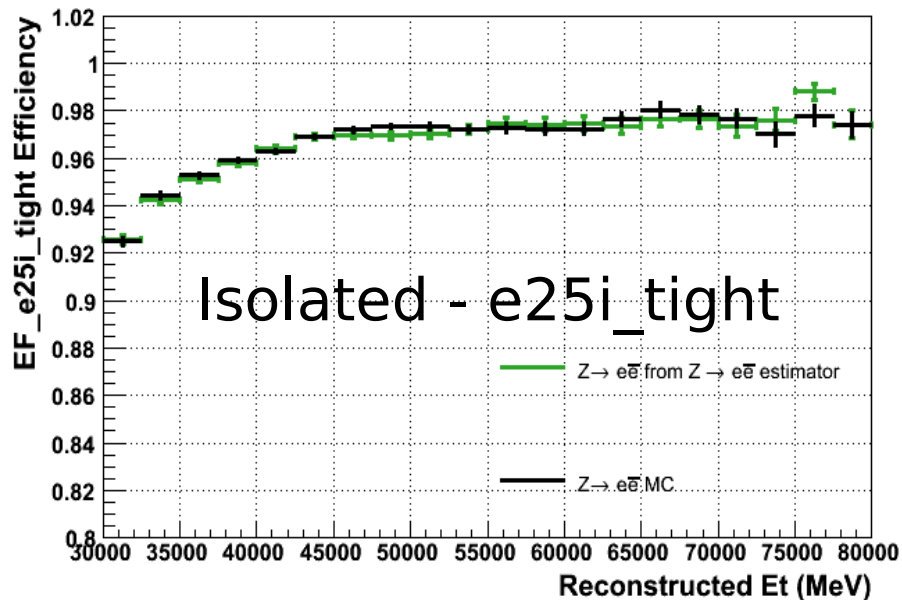
- Z- \rightarrow ee tag and probe is an example of a way to determine efficiency from data, validation against MC methods lots of times by lots of people, including by me.
- I will use Z- \rightarrow ee MC and assume these results can be determined from data.
- Z- \rightarrow ee MC will be used to construct an efficiency **estimator**.
 - This will provide a measurement of the trigger efficiency for an electron with given values of the N variables that affect trigger efficiency.

• Estimator efficiencies are then applied to electrons in other samples e.g. Z- \rightarrow ee, and to busier events such as ttbar, SUSY to see if the results agree with MC.



Et and Eta estimators applied to more Z->ee

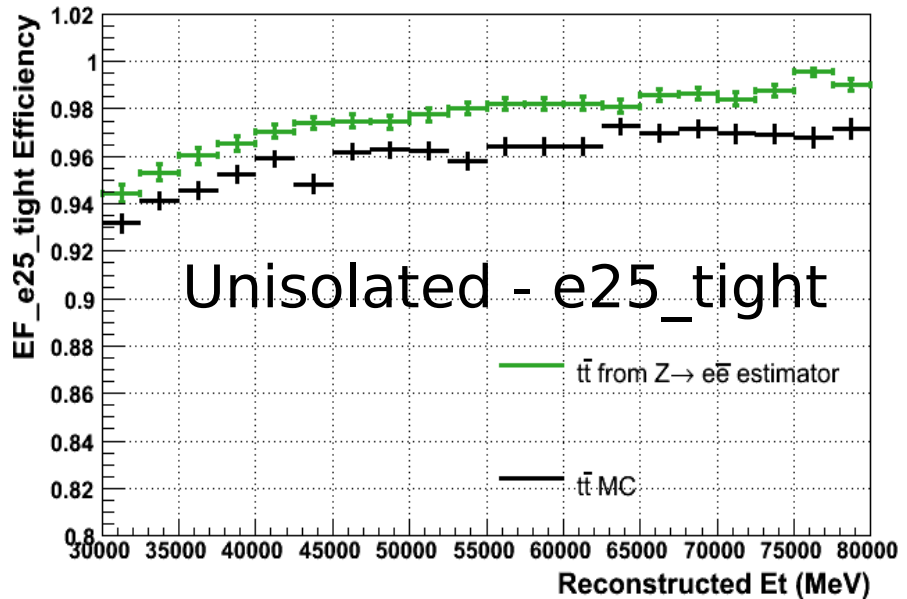
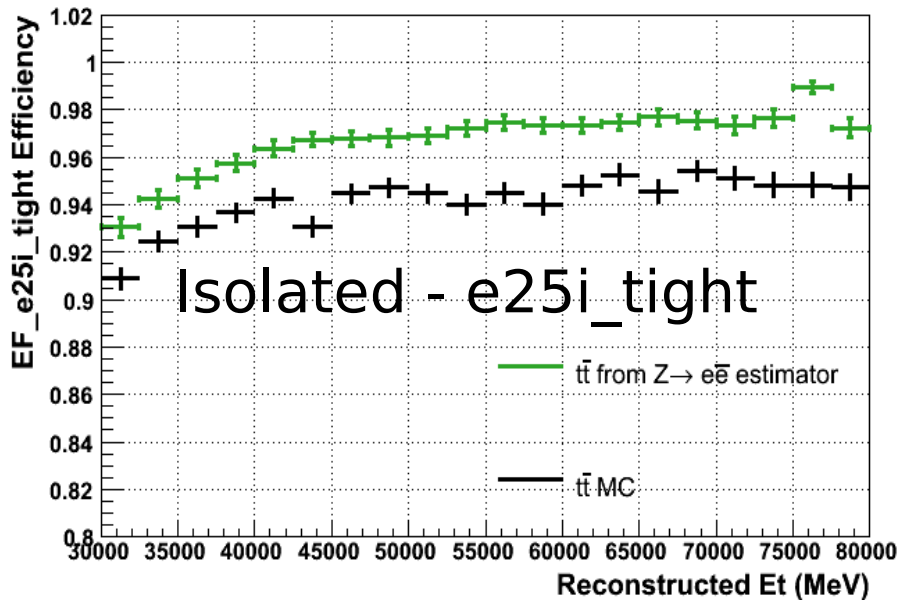
- Estimators constructed in 2D using **only Et and eta**.
- Efficiency vs Et using 2D Z->ee **estimators** is compared to **MC** below.
- For isolated (left) and unisolated (right) e25_tight triggers



- 2D **Estimators** seem to fully explaining trigger efficiency as shown by agreement between Z->ee efficiency from **MC** and estimators.
- Trigger efficiency in this case can be fully explained by Et and Eta kinematics alone.
- Electrons in Z->ee are isolated electrons

Et and Eta estimators applied to $t\bar{t}$

- Studies done in 2D using **only Et and eta**.
- Efficiency vs Et using 2D $Z \rightarrow e\bar{e}$ **estimators** is compared to $t\bar{t}$ **MC** below
- Isolated and unisolated triggers



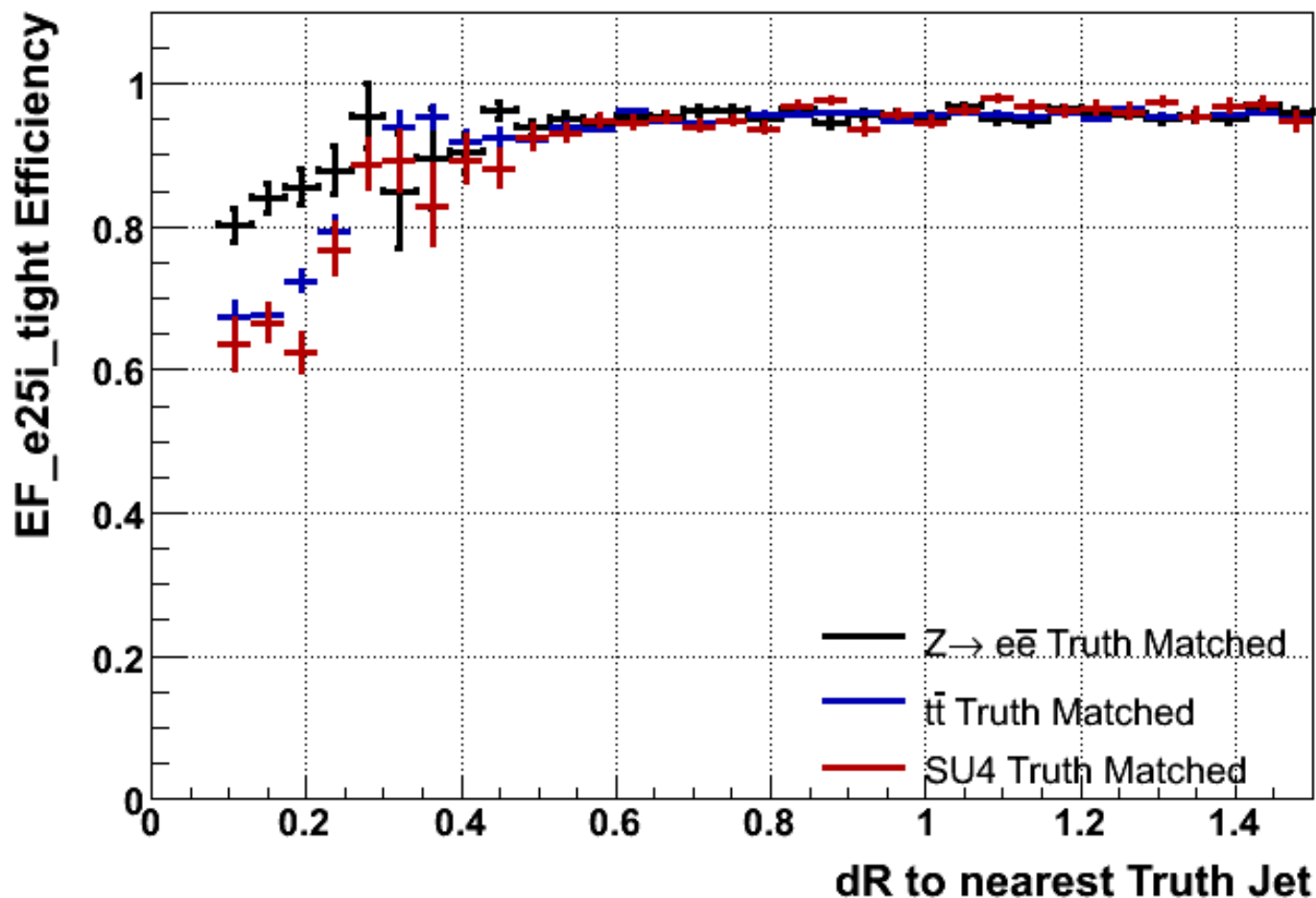
• 2D **Estimators** are not fully explaining trigger efficiency as shown by disagreement between $t\bar{t}$ efficiency from **MC** and **estimators**.

• Trigger efficiency in more busy events such as $t\bar{t}$ cannot be fully explained by Et and Eta kinematics alone.

• Other sources of differences... eg Different event topology leading to differences in isolation.

Event Topologies -- Isolation

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- Efficiency vs dR to nearest truth jet for $Z \rightarrow ee$, $t\bar{t}$ and SU4.

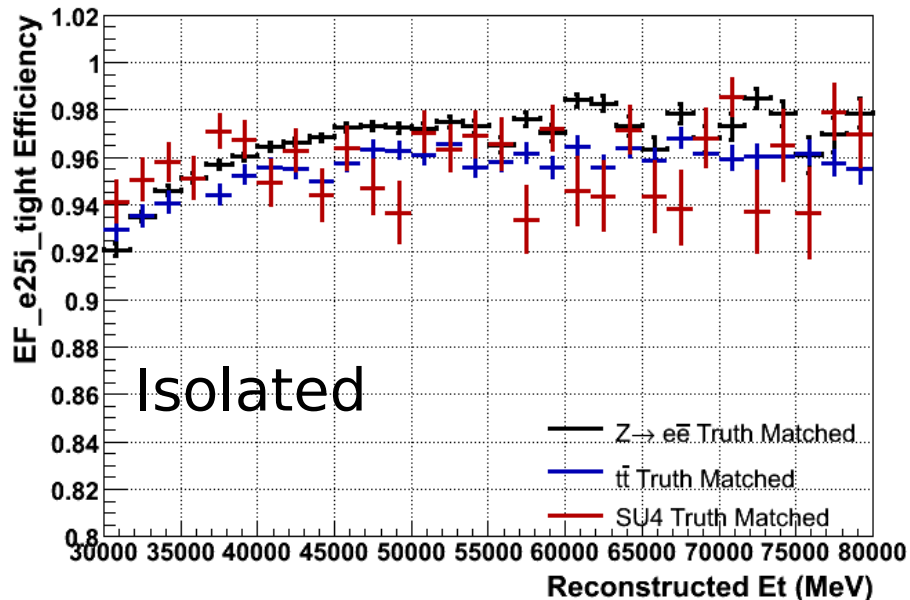
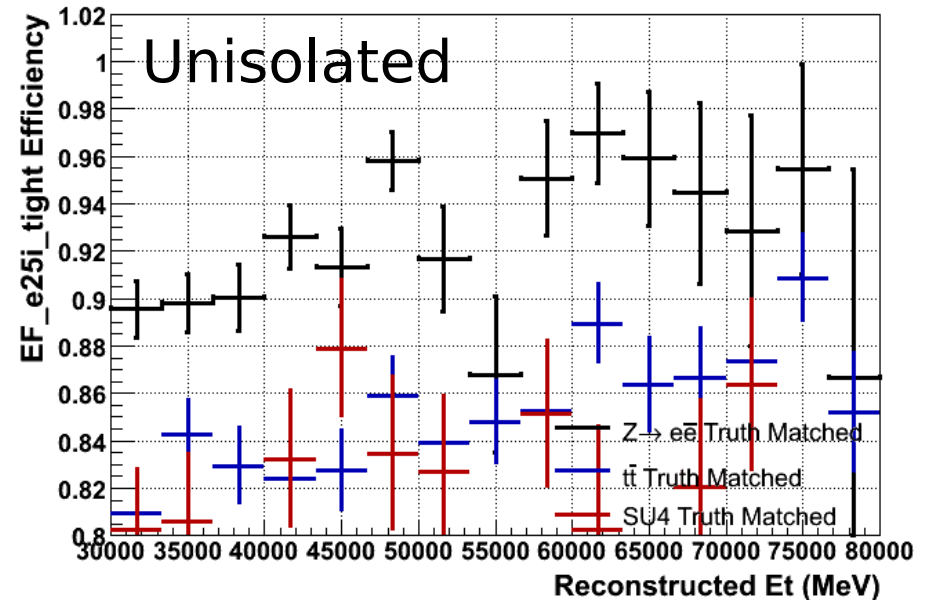
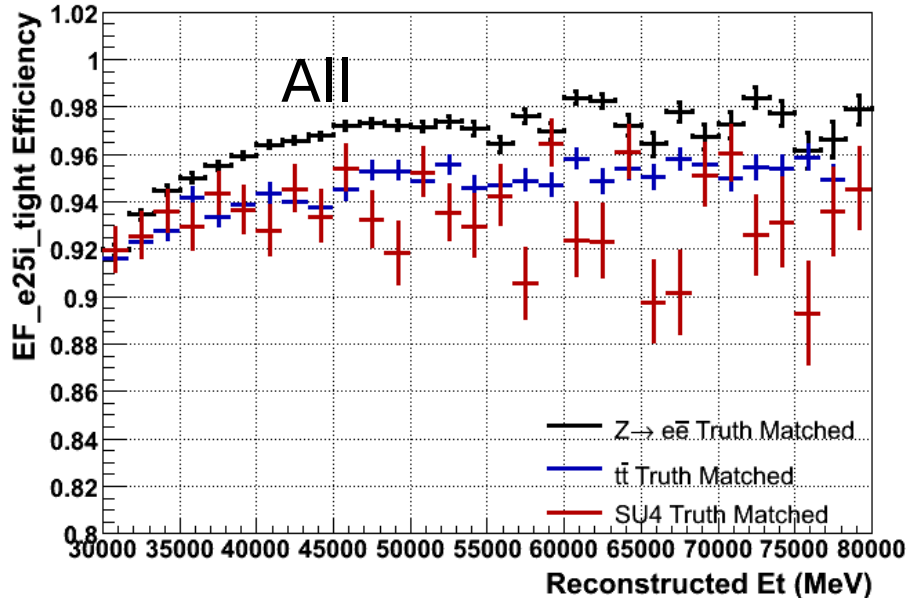
- Efficiency falls and differs when truth jets are within $dR < 0.6$ of an electron.

- Efficiency differences are caused by nearby truth jets.

- i.e Non-Isolation of electrons.

Isolated and Unisolated electrons

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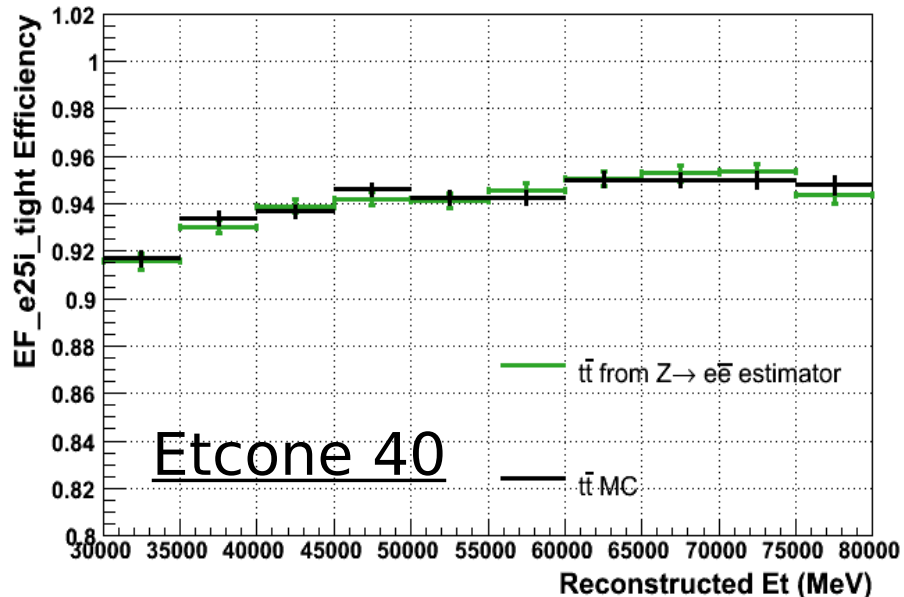
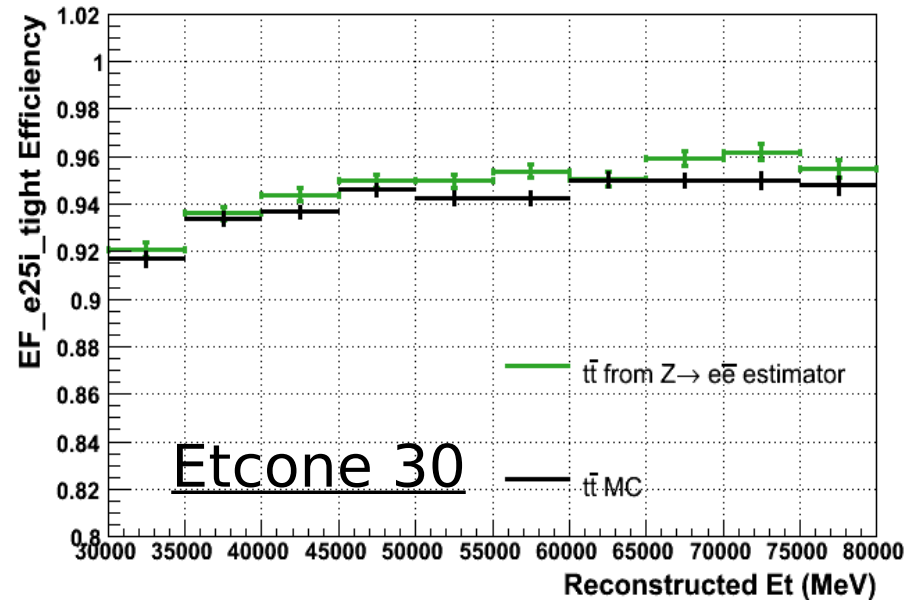
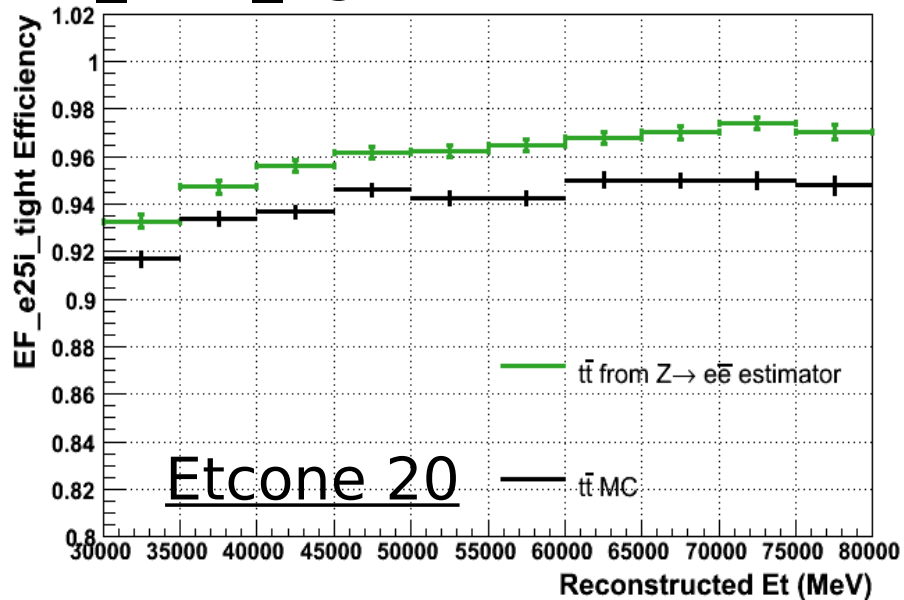


- Looking at efficiency for Isolated electrons (dR to truth jet > 0.6) and Unisolated electrons ($dR < 0.6$) separately.

- Better agreement after requiring Isolation from Truth Jets.

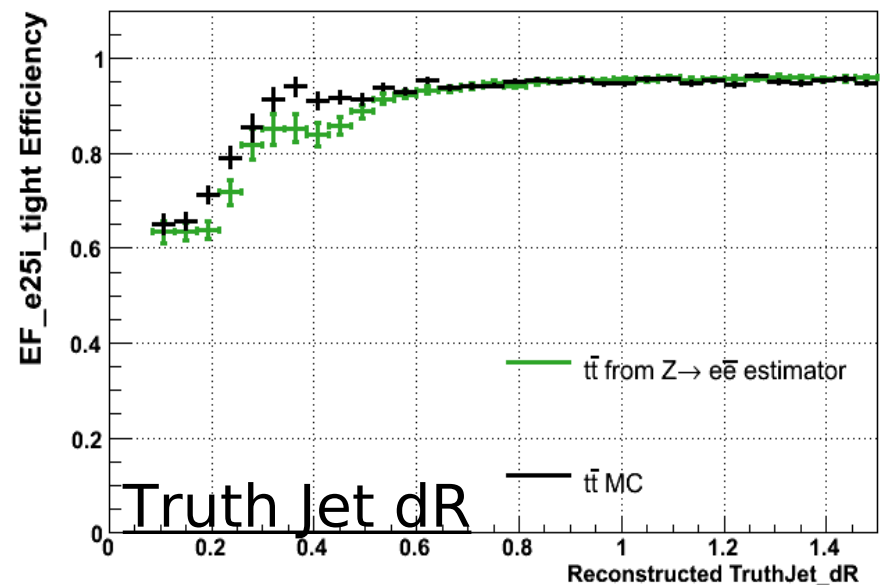
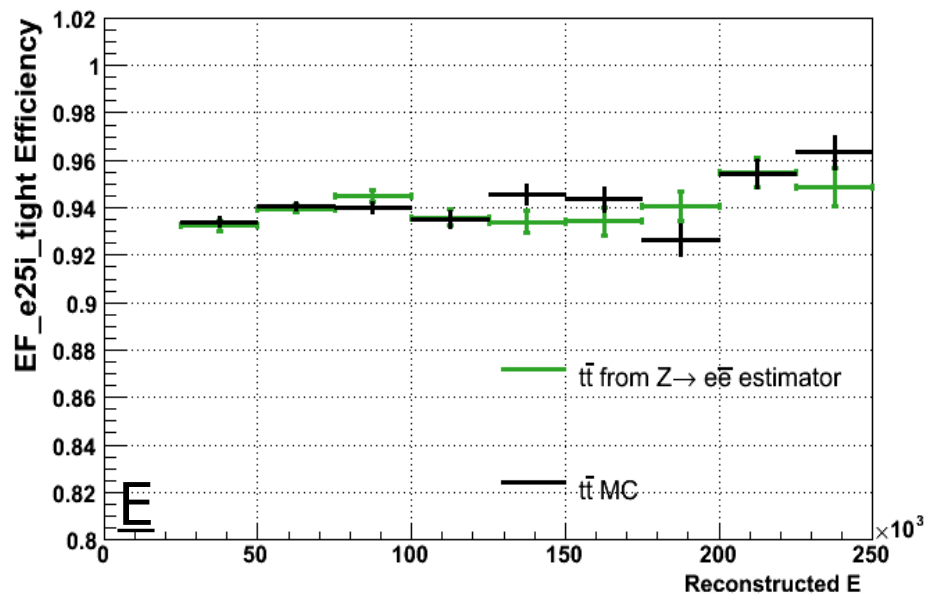
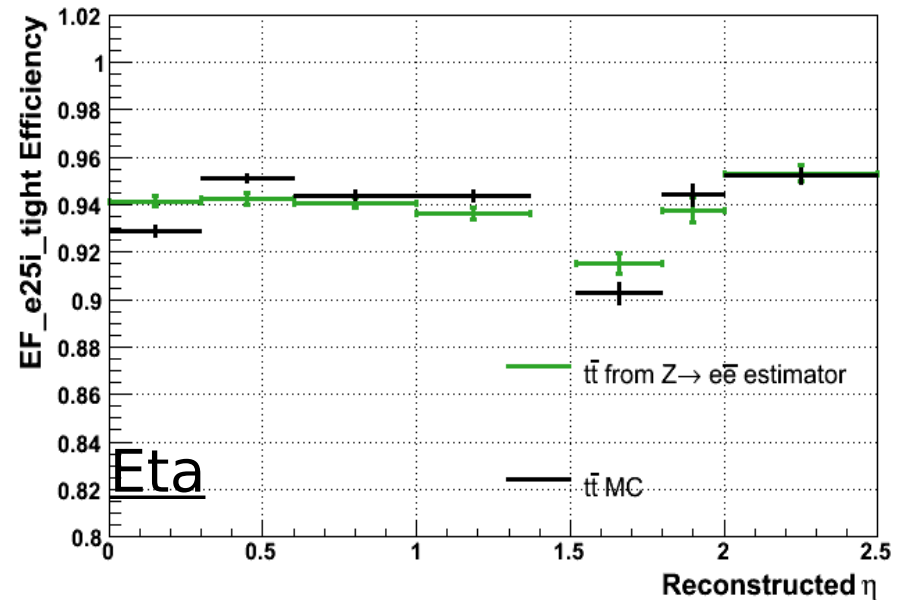
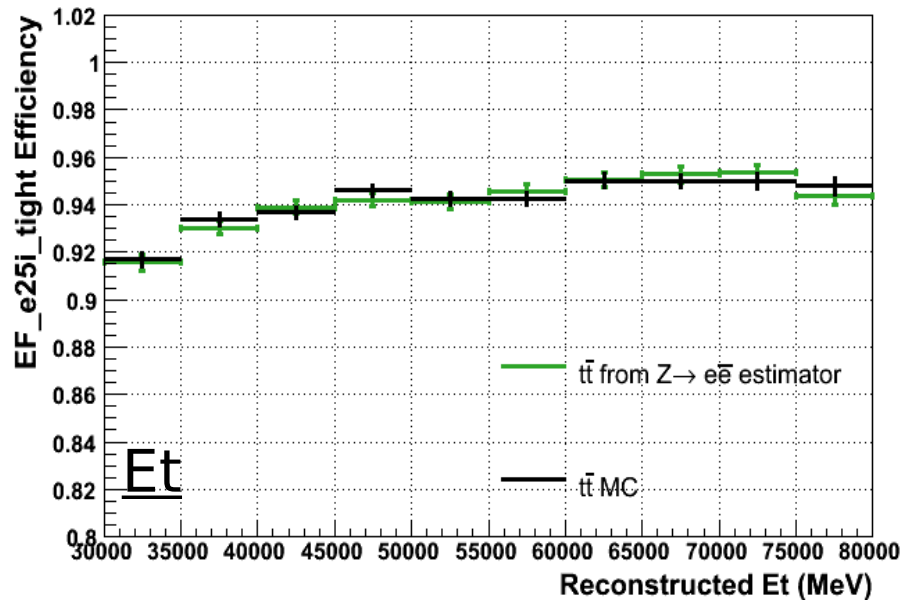
Estimators including isolation; Et+Eta+EtconeX

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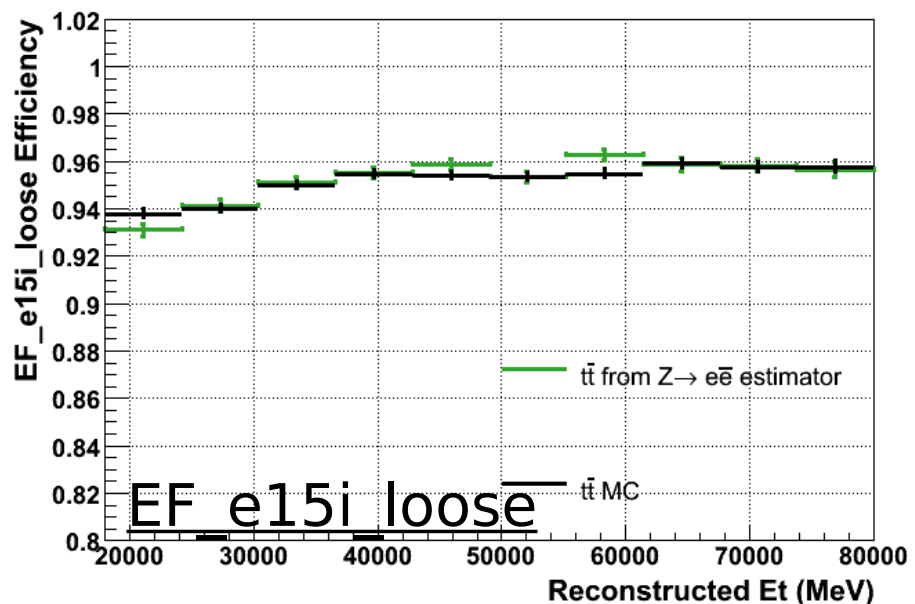
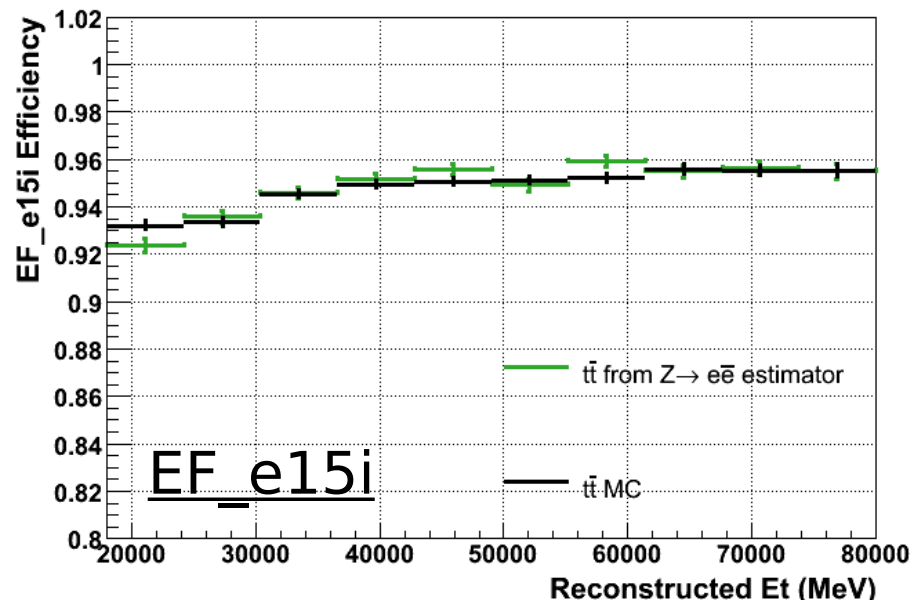
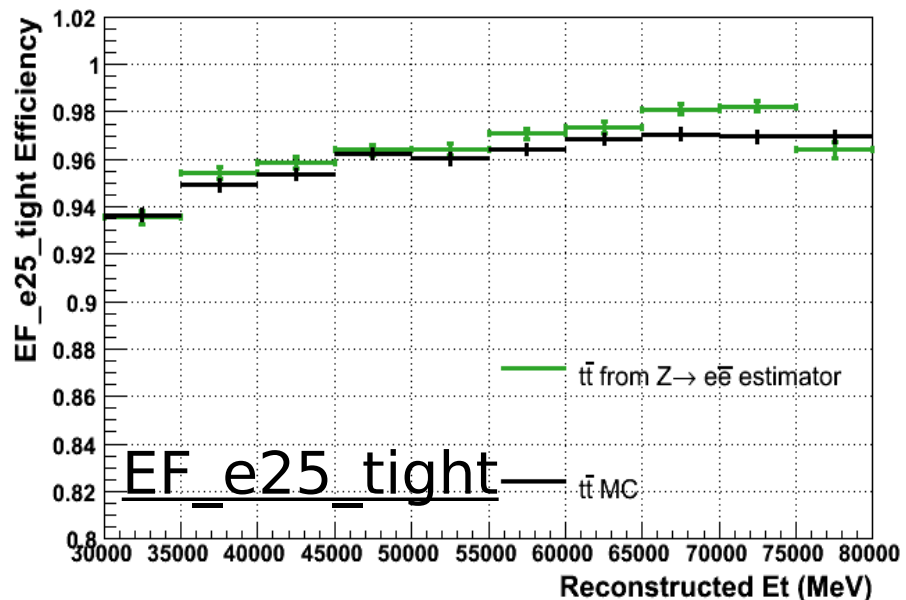
- Etcone contains information on the amount of energy in a cone around the electron.
- Different Etcones are used as a third Dimension in **estimators**.
- **Estimator** efficiencies agree with **MC** when **Etcone40** (dR cone of 0.4) is used as a third dimension.

Results EF_e25i_tight - other variables



- 3D **estimators** describe efficiency well as a function of all variables studied

Other Triggers



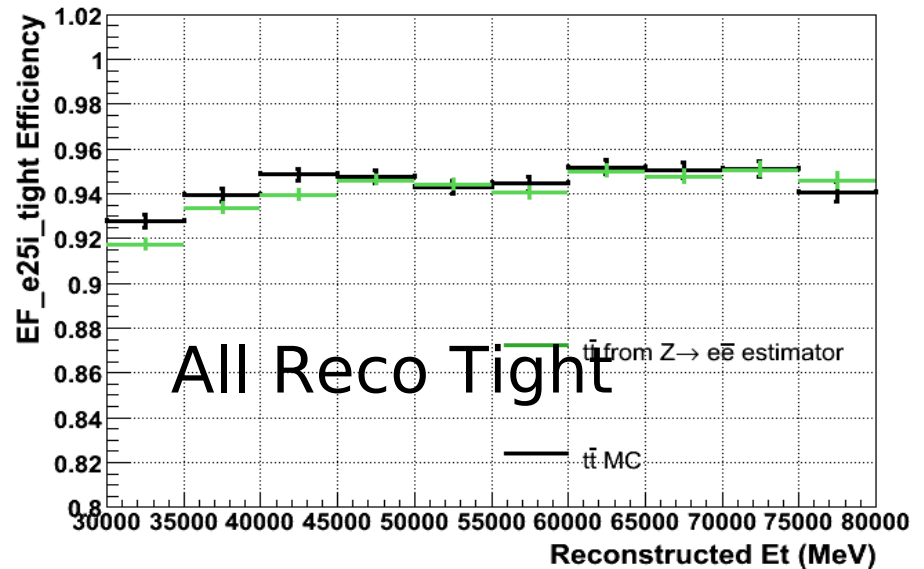
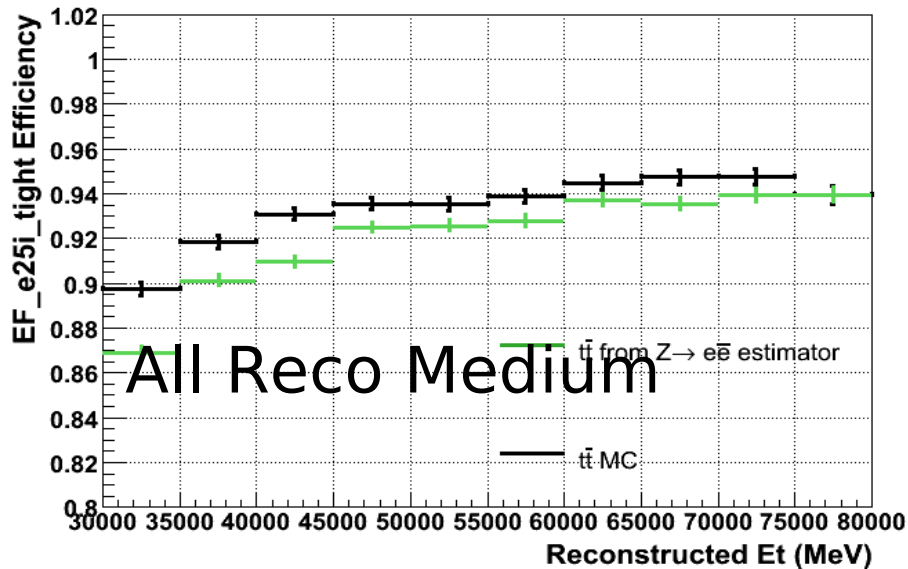
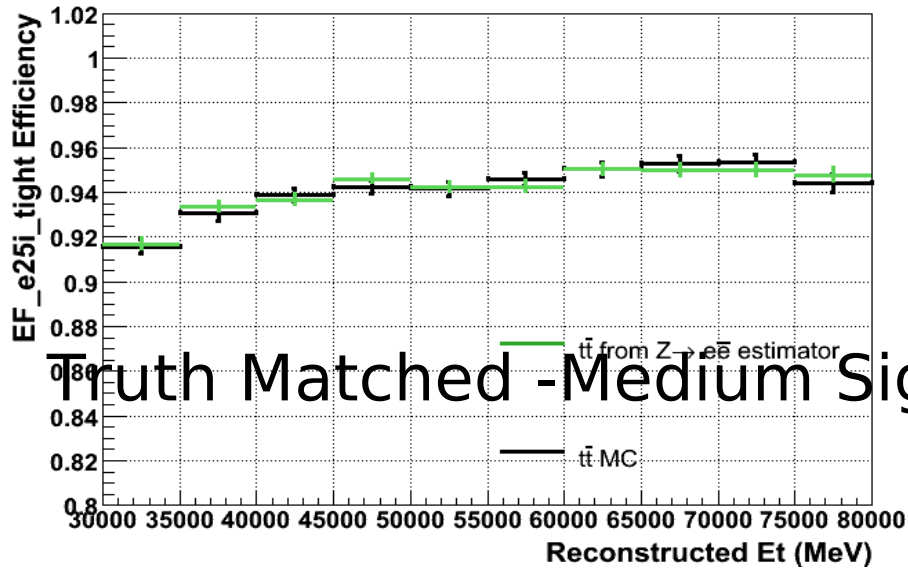
- 3D **estimators** describe efficiency well for all other triggers studied.

Conclusions

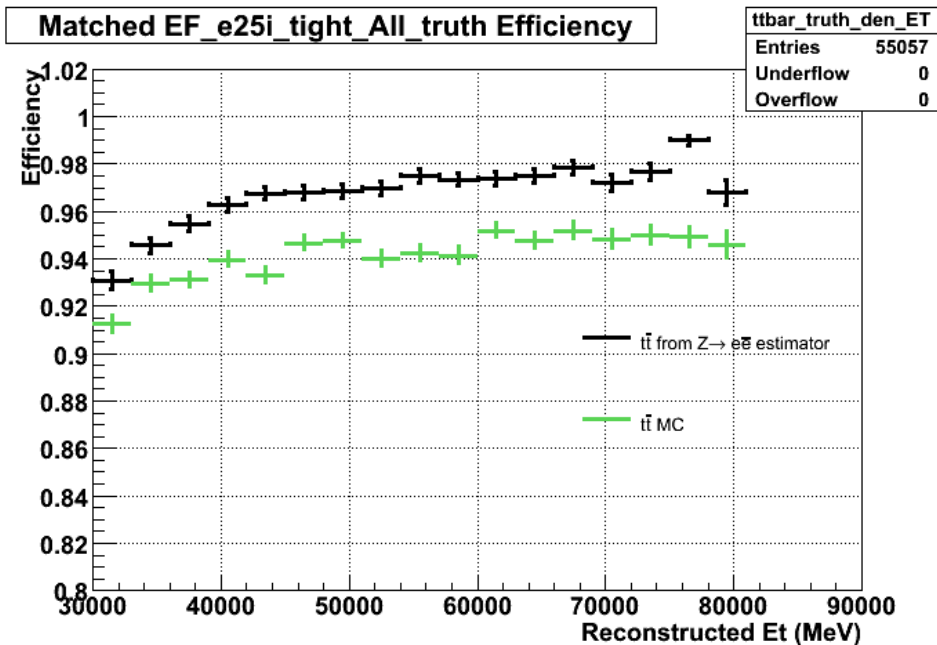
- Trigger efficiency for **isolated** electrons **can** be described by taking into electron **Et and Eta** dependencies alone.
- Trigger efficiency for **unisolated** electrons **cannot** be described by electron **Et and Eta** alone.
 - The extension to **3D** with **Etcone40** describing isolation is a promising method.
- 3D Estimators constructed from Z->ee tag and probe in real data provides a description of trigger efficiency for isolated and unisolated electrons that can be applied to different event topologies.

Back to Fakes

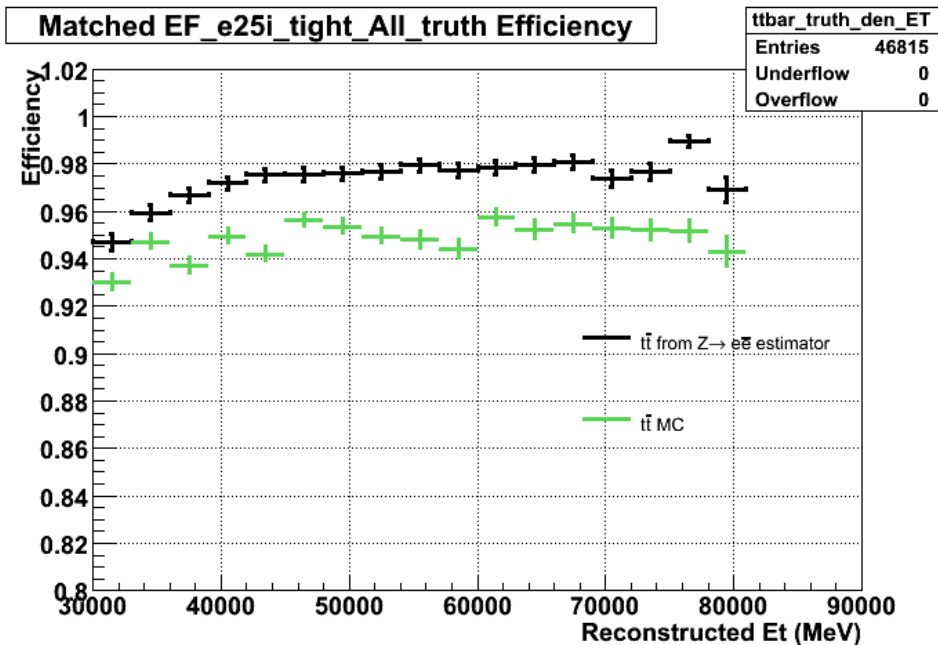
- How to deal with this?



Electron Kinematics



Truth Matched -- Medium



Truth Matched -- Tight